

During the past decade with increased computing power and new research developments, Bayesian statistical methods have become practical in diverse areas of statistical applications. Bayesian methods provide a unified framework for optimally combining information from multiple sources, resulting in simpler and improved statistical analyses. Despite the widespread growth in Bayesian methods, for the most the field of metrology has not taken advantage of these methods. Both NIST researchers and their customers have much to gain from these methods.

Institute/Organization: Information Technology Laboratory (ITL) , National Institute of Standards and Technology (NIST) , USA

Research Team: Charles Hagwood, charles.hagwood@nist.gov

Status : Going on

[Read more](#)